

**Notice of References Cited**

Application/Control No.

10/575,041

Applicant(s)/Patent Under  
Reexamination  
ADACHI ET AL.

Examiner

VINCENT T. TRAN

Art Unit

2115

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,345,240 B1	02-2002	Havens, Joseph Harold	703/21
*	B	US-2003/0229662 A1	12-2003	Luick, David Arnold	709/106
*	C	US-2005/0216775 A1	09-2005	Inoue, Keisuke	713/300
*	D	US-6,047,248 A	04-2000	Georgiou et al.	702/132
*	E	US-5,913,068 A	06-1999	Matoba, Tsukasa	713/322
*	F	US-2005/0081181 A1	04-2005	Brokenshire et al.	717/100
*	G	US-6,718,475 B2	04-2004	Cai, Zhong-Ning	713/323
*	H	US-2005/0071843 A1	03-2005	Guo et al.	718/101
*	I	US-2003/0110012 A1	06-2003	Orenstien et al.	702/188
*	J	US-7,062,304 B2	06-2006	Chauvel et al.	455/574
*	K	US-2004/0037346 A1	02-2004	Rusu et al.	374/121
*	L	US-6,938,176 B1	08-2005	Alben et al.	713/323
*	M	US-2005/0278520 A1	12-2005	Hirai et al.	713/001

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 03/083693 A1	09-2003	JP	Hirai et al.	G06F 9/00
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.